Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	576	716/3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/29 15:26
L2	1541	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/29 15:26
L3	3133	((700/121) or (382/144,145) or (716/19,21)).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/29 15:28
L4	9141	((700/121) or (382/144,145) or (716/19,21)).ccls. and cad and electron near 3 beam and inspect$3 and (cover$4 or translat$4) and (verif$6 or check$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/29 15:31
L5	57	((700/121) or (382/144,145) or (716/19,21)).ccls. and cad and electron near3 beam and inspect$3 and (conver$4 or translat$4) and (verif$6 or check$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/29 15:32
S1	1274	716/19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/24 13:03
S2	851	716/21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 15:15
S3	1	(716/19).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data adj verification)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 15:19
S4	0	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data adj verification)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 15:19

S5	1	("716"/$).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data adj verification)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 15:20
S6	3	(mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data adj verification)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 15:22
S7	42	(mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data same (verification or inspection))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 16:13
S8	10	(mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data adj (verification or inspection))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 16:25
S9	4	(mask or reticle) and (CAD same ((electron adj beam) or EB)) and (data adj conversion) and (data adj (verification or inspection))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/26 16:25
S10	1722	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/24 13:03
S11	0	(716/5).ccls. and (mask oe reticle) and (CAD adj (data or design)) and (((electron adj beam) or EB) adj (write adj data) same (conver$) same (inspection adj data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/24 13:09
S12	0	(716/5).ccls. and (mask or reticle) and (CAD adj (data or design)) and (((electron adj beam) or EB) adj (write adj data) same (conver$) same (inspection adj data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/24 13:09
S13	1	("716"/$).ccls. and (mask or reticle) and (CAD adj (data or design)) and (((electron adj beam) or EB) adj (write adj data) same (conver$) same (inspection adj data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/24 13:10

S14	2	(mask or reticle) and (CAD adj (data or design)) and (((electron adj beam) or EB) adj (write adj data) same (conver$) same (inspection adj data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/24 13:10